LM5106 100V Half Bridge Gate Driver with Programmable Dead-Time

Check for Samples: LM5106

FEATURES

- **Drives Both a High Side and Low Side N-Channel MOSFET**
- **1.8A Peak Output Sink Current**
- **1.2A Peak Output Source Current**
- **Bootstrap Supply Voltage Range up to 118V DC**
- **Single TTL Compatible Input**
- **Programmable Turn-On Delays (Dead-Time)**
- **Enable Input Pin**
- **Fast Turn-Off Propagation Delays (32ns Typical)**
- **Drives 1000pF with 15ns Rise and 10ns Fall Time**
- **Supply Rail Under-Voltage Lockout**
- **Low Power Consumption**

APPLICATIONS

- **Solid State Motor Drives**
- **Half and Full Bridge Power Converters**
- **Two Switch Forward Power Converters**

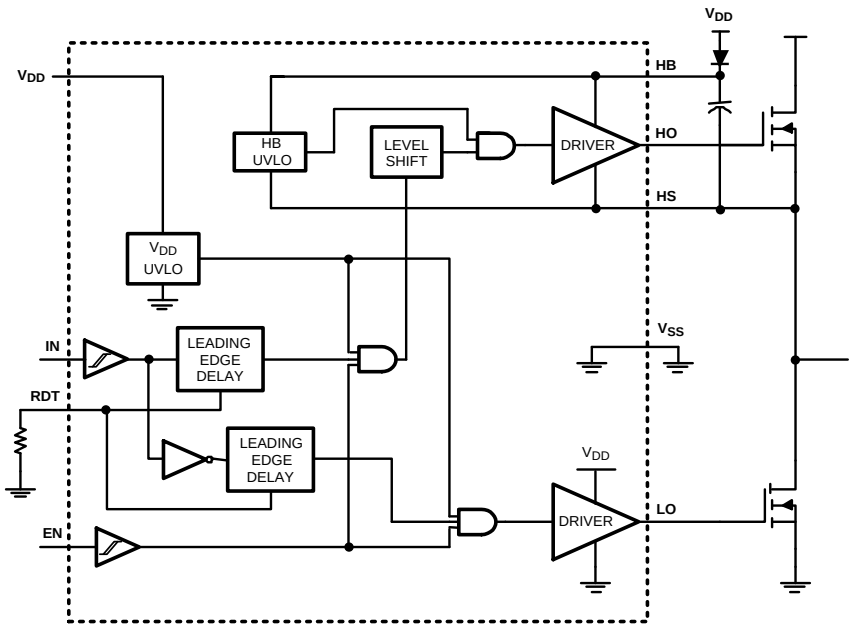
PACKAGE

- **WSON-10 (4 mm x 4 mm)**
- **VSSOP-10**

DESCRIPTION

The LM5106 is a high voltage gate driver designed to drive both the high side and low side N-Channel MOSFETs in a synchronous buck or half bridge configuration. The floating high side driver is capable of working with rail voltages up to 100V. The single control input is compatible with TTL signal levels and a single external resistor programs the switching transition dead-time through tightly matched turn-on delay circuits. The robust level shift technology operates at high speed while consuming low power and provides clean output transitions. Under-voltage lockout disables the gate driver when either the low side or the bootstrapped high side supply voltage is below the operating threshold. The LM5106 is offered in the VSSOP-10 or thermally enhanced 10-pin WSON plastic package.

Simplified Block Diagram



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Connection Diagram

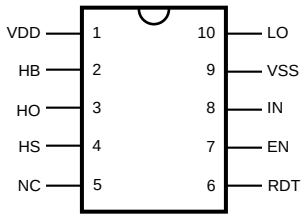


Figure 1. 10-Lead VSSOP or WSON
See DGS or DPR0010A Package

PIN DESCRIPTIONS

Pin #	Name	Description	Application Information
1	VDD	Positive gate drive supply	Decouple VDD to VSS using a low ESR/ESL capacitor, placed as close to the IC as possible.
2	HD	High side gate driver bootstrap rail	Connect the positive terminal of bootstrap capacitor to the HB pin and connect negative terminal to HS. The Bootstrap capacitor should be placed as close to IC as possible.
3	HO	High side gate driver output	Connect to the gate of high side N-MOS device through a short, low inductance path.
4	HS	High side MOSFET source connection	Connect to the negative terminal of the bootststrap capacitor and to the source of the high side N-MOS device.
5	NC	Not Connected	
6	RDT	Dead-time programming pin	A resistor from RDT to VSS programs the turn-on delay of both the high and low side MOSFETs. The resistor should be placed close to the IC to minimize noise coupling from adjacent PC board traces.
7	EN	Logic input for driver Disable/Enable	TTL compatible threshold with hysteresis. LO and HO are held in the low state when EN is low.
8	IN	Logic input for gate driver	TTL compatible threshold with hysteresis. The high side MOSFET is turned on and the low side MOSFET turned off when IN is high.
9	VSS	Ground return	All signals are referenced to this ground.
10	LO	Low side gate driver output	Connect to the gate of the low side N-MOS device with a short, low inductance path.
NA	EP	Exposed Pad	The exposed pad has no electrical contact. Connect to system ground plane for reduced thermal resistance.

These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

Absolute Maximum Ratings[1][2]

V_{DD} to V_{SS}	–0.3V to +18V
HB to HS	–0.3V to +18V
IN and EN to V_{SS}	–0.3V to V_{DD} + 0.3V
LO to V_{SS}	–0.3V to V_{DD} + 0.3V
HO to V_{SS}	HS – 0.3V to HB + 0.3V
HS to V_{SS}[3]	−5V to +100V
HB to V_{SS}	118V
RDT to V_{SS}	–0.3V to 5V
Junction Temperature	+150°C
Storage Temperature Range	–55°C to +150°C
ESD Rating HBM[4]	1.5 kV

(1) Absolute Maximum Ratings indicate limits beyond which damage to the component may occur. Operating Ratings are conditions under which operation of the device is ensured. Operating Ratings do not imply ensured performance limits. For ensured performance limits and associated test conditions, see the Electrical Characteristics.
(2) If Military/Aerospace specified devices are required, please contact the Texas Instruments Sales Office/Distributors for availability and specifications.
(3) In the application the HS node is clamped by the body diode of the external lower N-MOSFET, therefore the HS voltage will generally not exceed -1V. However in some applications, board resistance and inductance may result in the HS node exceeding this stated voltage transiently. If negative transients occur on HS, the HS voltage must never be more negative than V_{DD} - 15V. For example, if V_{DD} = 10V, the negative transients at HS must not exceed -5V.
(4) The human body model is a 100 pF capacitor discharged through a 1.5kΩ resistor into each pin. Pin 2, Pin 3 and Pin 4 are rated at 500V.

Recommended Operating Conditions

V_{DD}	+8V to +14V
HS[1]	–1V to 100V
HB	HS + 8V to HS + 14V
HS Slew Rate	< 50V/ns
Junction Temperature	–40°C to +125°C

(1) In the application the HS node is clamped by the body diode of the external lower N-MOSFET, therefore the HS voltage will generally not exceed -1V. However in some applications, board resistance and inductance may result in the HS node exceeding this stated voltage transiently. If negative transients occur on HS, the HS voltage must never be more negative than V_{DD} - 15V. For example, if V_{DD} = 10V, the negative transients at HS must not exceed -5V.

Electrical Characteristics

Specifications in standard typeface are for T_J = +25°C, and those in **boldface type** apply over the full **operating junction temperature range**. Unless otherwise specified, V_{DD} = HB = 12V, V_{SS} = HS = 0V, EN = 5V. No load on LO or HO. RDT= 100kΩ[1].

Symbol	Parameter	Conditions	Min	Typ	Max	Units
SUPPLY CURRENTS						
I_{DD}	V_{DD} Quiescent Current	IN = EN = 0V		0.34	**0.6**	mA
I_{DDO}	V_{DD} Operating Current	f = 500 kHz		2.1	**3.5**	mA
I_{HB}	Total HB Quiescent Current	IN = EN = 0V		0.06	**0.2**	mA
I_{HBO}	Total HB Operating Current	f = 500 kHz		1.5	**3**	mA
I_{HBS}	HB to V_{SS} Current, Quiescent	HS = HB = 100V		0.1	**10**	µA
I_{HBSO}	HB to V_{SS} Current, Operating	f = 500 kHz		0.5		mA
INPUT IN and EN						
V_{IL}	Low Level Input Voltage Threshold		**0.8**	1.8		V
V_{IH}	High Level Input Voltage Threshold			1.8	**2.2**	V
R_{pd}	Input Pulldown Resistance Pin IN and EN		**100**	200	**500**	kΩ

(1) Min and Max limits are 100% production tested at 25°C. Limits over the operating temperature range are ensured through correlation using Statistical Quality Control (SQC) methods. Limits are used to calculate Average Outgoing Quality Level (AOQL).

Electrical Characteristics (continued)

Specifications in standard typeface are for T_J = +25°C, and those in **boldface type** apply over the full **operating junction temperature range**. Unless otherwise specified, V_{DD} = HB = 12V, V_{SS} = HS = 0V, EN = 5V. No load on LO or HO. RDT= 100kΩ(1).

Symbol	Parameter	Conditions	Min	Typ	Max	Units
DEAD-TIME CONTROLS						
VRDT	Nominal Voltage at RDT		**2.7**	3	**3.3**	V
IRDT	RDT Pin Current Limit	RDT = 0V	**0.75**	1.5	**2.25**	mA
UNDER VOLTAGE PROTECTION						
V_{DDR}	V_{DD} Rising Threshold		**6.2**	6.9	**7.6**	V
V_{DDH}	V_{DD} Threshold Hysteresis			0.5		V
V_{HBR}	HB Rising Threshold		**5.9**	6.6	**7.3**	V
V_{HBH}	HB Threshold Hysteresis			0.4		V
LO GATE DRIVER						
V_{OLL}	Low-Level Output Voltage	I_{LO} = 100 mA		0.21	**0.4**	V
V_{OHL}	High-Level Output Voltage	I_{LO} = –100 mA, $V_{OHL} = V_{DD} – V_{LO}$		0.5	**0.85**	V
I_{OHL}	Peak Pullup Current	LO = 0V		1.2		A
I_{OLL}	Peak Pulldown Current	LO = 12V		1.8		A
HO GATE DRIVER						
V_{OLH}	Low-Level Output Voltage	I_{HO} = 100 mA		0.21	**0.4**	V
V_{OHH}	High-Level Output Voltage	I_{HO} = –100 mA, V_{OHH} = HB – HO		0.5	**0.85**	V
I_{OHH}	Peak Pullup Current	HO = 0V		1.2		A
I_{OLH}	Peak Pulldown Current	HO = 12V		1.8		A
THERMAL RESISTANCE						
θ_{JA}	Junction to Ambient	See(2)(3)		40		°C/W

(2) 4 layer board with Cu finished thickness 1.5/1.0/1.0/1.5 oz. Maximum die size used. 5x body length of Cu trace on PCB top. 50 x 50mm ground and power planes embedded in PCB. See Application Note AN-1187.
(3) The θ_{JA} is not a constant for the package and depends on the printed circuit board design and the operating conditions.

Switching Characteristics

Specifications in standard typeface are for T_J = +25°C, and those in **boldface type** apply over the full **operating junction temperature range**. Unless otherwise specified, V_{DD} = HB = 12V, V_{SS} = HS = 0V, No Load on LO or HO(1).

Symbol	Parameter	Conditions	Min	Typ	Max	Units
t_{LPHL}	Lower Turn-Off Propagation Delay			32	**56**	ns
t_{HPHL}	Upper Turn-Off Propagation Delay			32	**56**	ns
t_{LPLH}	Lower Turn-On Propagation Delay	RDT = 100k	**400**	520	**640**	ns
t_{HPLH}	Upper Turn-On Propagation Delay	RDT = 100k	**450**	570	**690**	ns
t_{LPLH}	Lower Turn-On Propagation Delay	RDT = 10k	**85**	115	**160**	ns
t_{HPLH}	Upper Turn-On Propagation Delay	RDT = 10k	**85**	115	**160**	ns
t_{en}, t_{sd}	Enable and Shutdown propagation delay			36		ns
DT1, DT2	Dead-time LO OFF to HO ON & HO OFF to LO ON	RDT = 100k		510		ns
		RDT = 10k		86		ns
MDT	Dead-time matching	RDT = 100k		50		ns
t_R	Either Output Rise Time	C_L = 1000pF		15		ns
t_F	Either Output Fall Time	C_L = 1000pF		10		ns

(1) Min and Max limits are 100% production tested at 25°C. Limits over the operating temperature range are ensured through correlation using Statistical Quality Control (SQC) methods. Limits are used to calculate Average Outgoing Quality Level (AOQL).

Typical Performance Characteristics

V_{DD} Operating Current vs Frequency

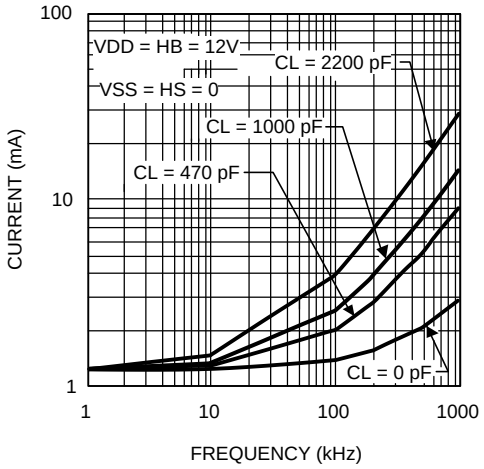


Figure 2.

Operating Current vs Temperature

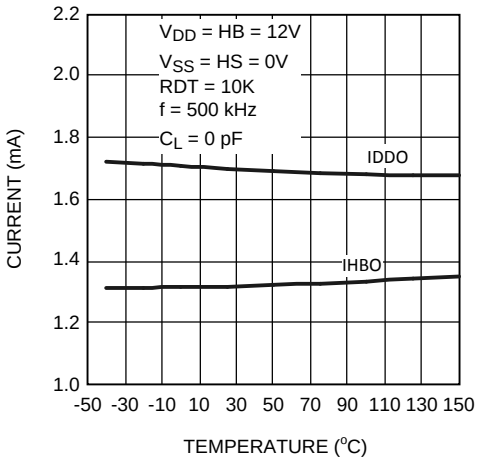


Figure 3.

Quiescent Current vs Supply Voltage

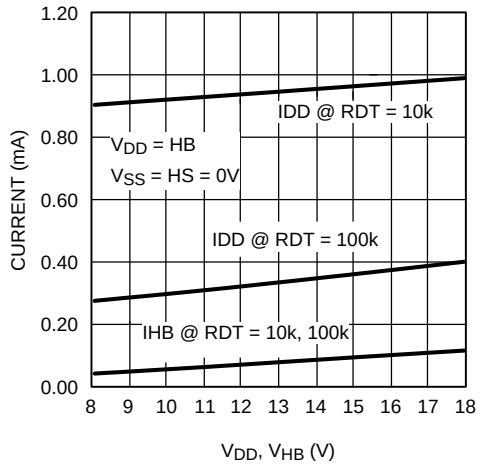


Figure 4.

Quiescent Current vs Temperature

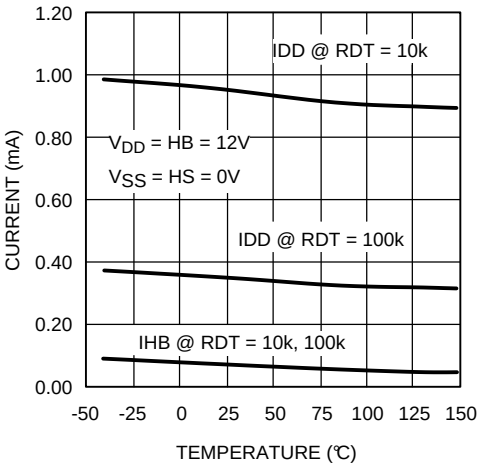


Figure 5.

HB Operating Current vs Frequency

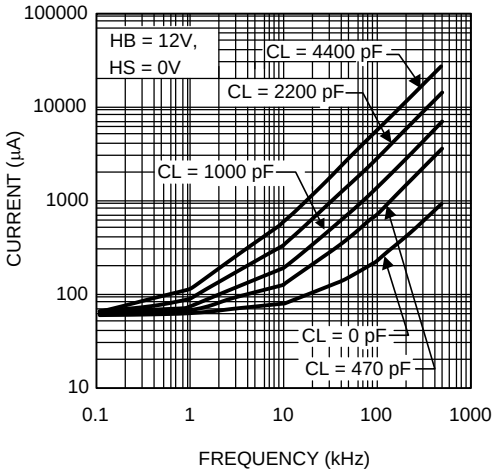


Figure 6.

HO & LO Peak Output Current vs Output Voltage

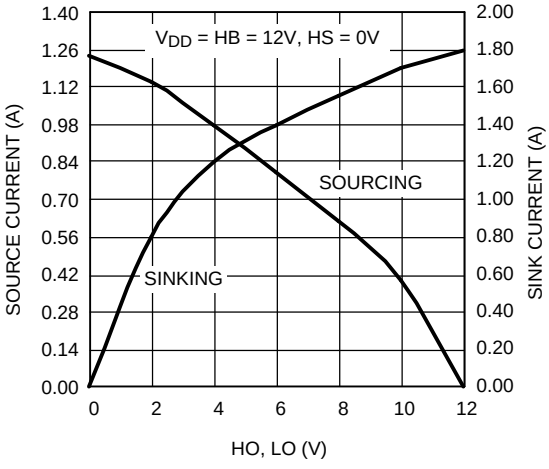


Figure 7.

Typical Performance Characteristics (continued)

Undervoltage Rising Threshold vs Temperature

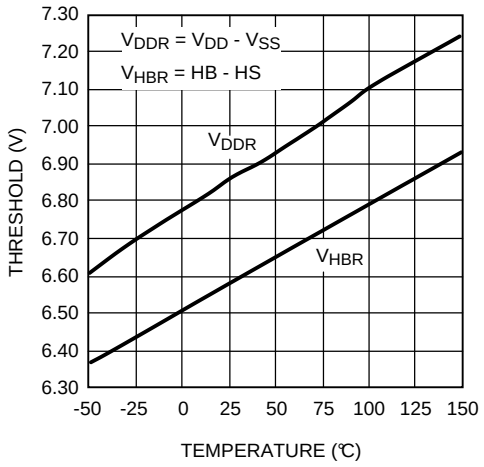


Figure 8.

Undervoltage Hysteresis vs Temperature

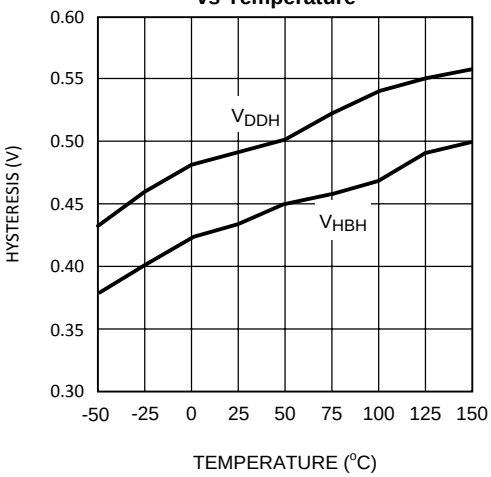


Figure 9.

LO & HO - Low Level Output Voltage vs Temperature

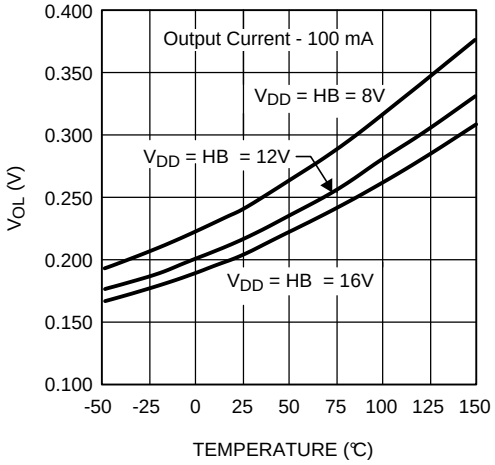


Figure 10.

LO & HO - High Level Output Voltage vs Temperature

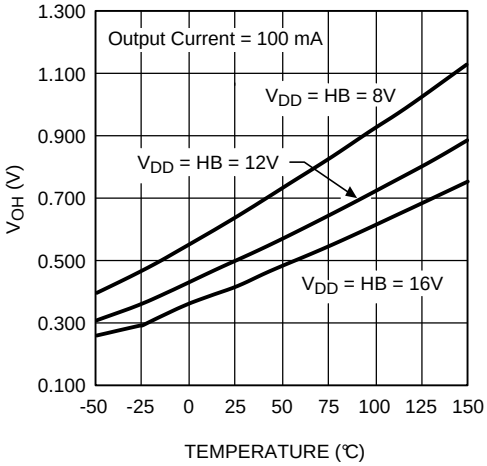


Figure 11.

Input Threshold vs Temperature

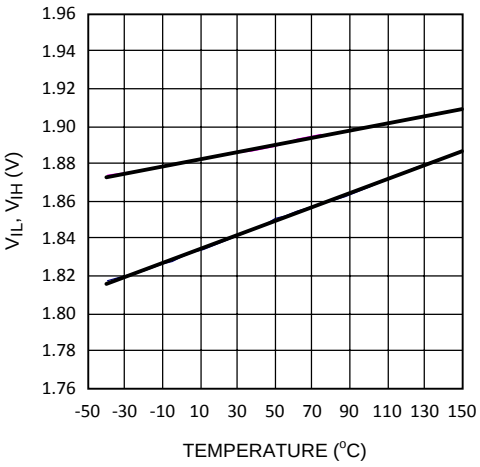


Figure 12.

Dead-Time vs RT Resistor Value

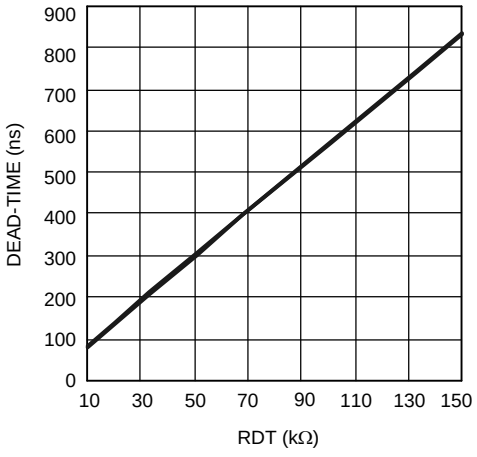


Figure 13.

Typical Performance Characteristics (continued)

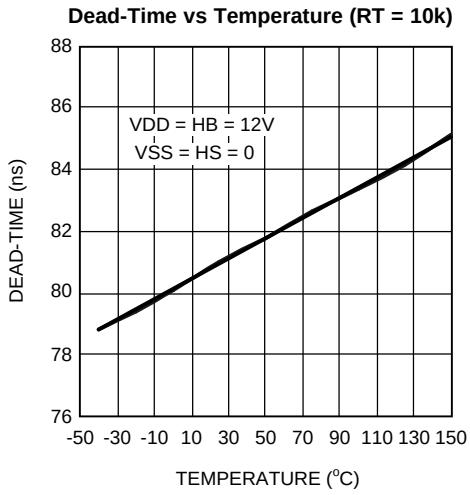


Figure 14.

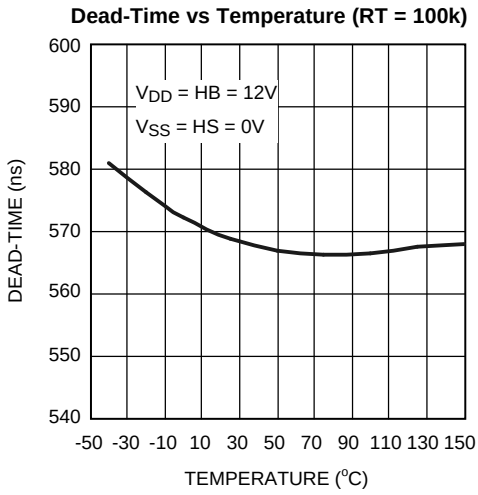


Figure 15.

Timing Diagrams

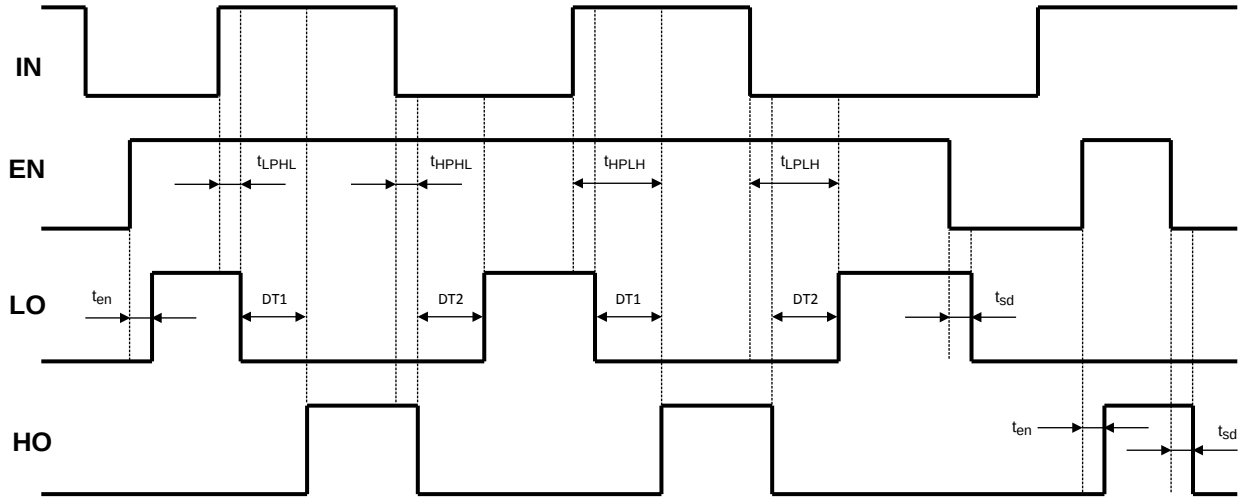


Figure 16. LM5106 Input - Output Waveforms

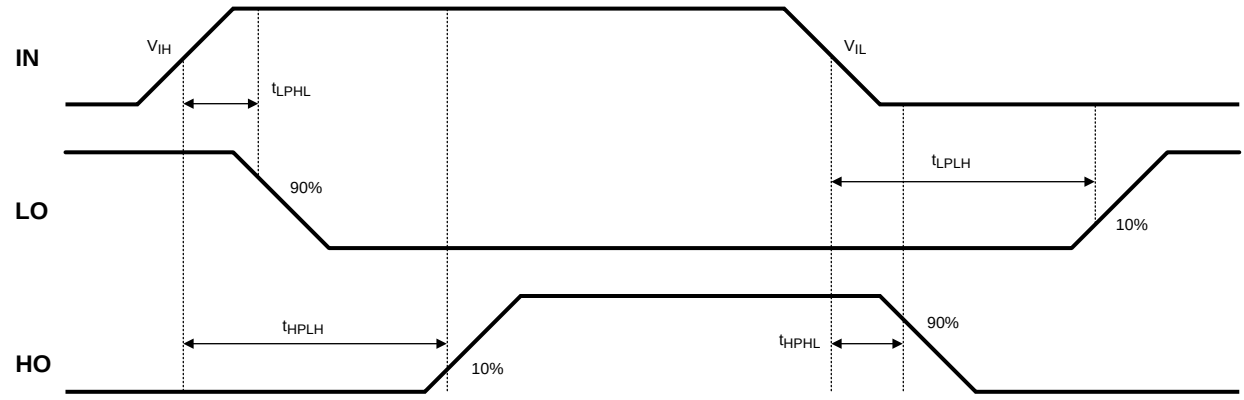


Figure 17. LM5106 Switching Time Definitions: t_{LPLH}, t_{LPHL}, t_{HPLH}, t_{HPHL}

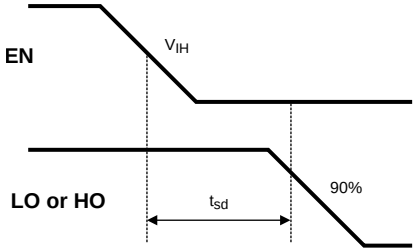


Figure 18. LM5106 Enable: t_{sd}

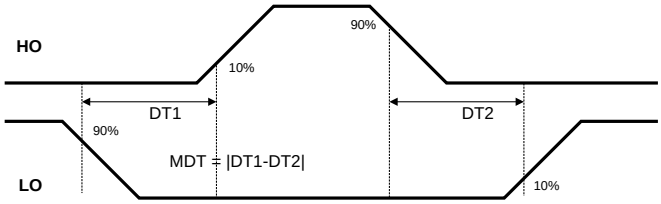


Figure 19. LM5106 Dead-time: DT

Operational Notes

The LM5106 is a single PWM input Gate Driver with Enable that offers a programmable dead-time. The dead-time is set with a resistor at the RDT pin and can be adjusted from 100ns to 600ns. The wide dead-time programming range provides the flexibility to optimize drive signal timing for a wide range of MOSFETS and applications.

The RDT pin is biased at 3V and current limited to 1 mA maximum programming current. The time delay generator will accommodate resistor values from 5k to 100k with a dead-time time that is proportional to the RDT resistance. Grounding the RDT pin programs the LM5106 to drive both outputs with minimum dead-time.

STARTUP AND UVLO

Both top and bottom drivers include under-voltage lockout (UVLO) protection circuitry which monitors the supply voltage (V_{DD}) and bootstrap capacitor voltage (HB – HS) independently. The UVLO circuit inhibits each driver until sufficient supply voltage is available to turn-on the external MOSFETs, and the UVLO hysteresis prevents chattering during supply voltage transitions. When the supply voltage is applied to the V_{DD} pin of the LM5106, the top and bottom gates are held low until V_{DD} exceeds the UVLO threshold, typically about 6.9V. Any UVLO condition on the bootstrap capacitor will disable only the high side output (HO).

LAYOUT CONSIDERATIONS

The optimum performance of high and low side gate drivers cannot be achieved without taking due considerations during circuit board layout. The following points are emphasized:

1. Low ESR / ESL capacitors must be connected close to the IC between VDD and VSS pins and between HB and HS pins to support high peak currents being drawn from VDD and HB during the turn-on of the external MOSFETs.
2. To prevent large voltage transients at the drain of the top MOSFET, a low ESR electrolytic capacitor and a good quality ceramic capacitor must be connected between the MOSFET drain and ground (VSS).
3. In order to avoid large negative transients on the switch node (HS) pin, the parasitic inductances between the source of the top MOSFET and the drain of the bottom MOSFET (synchronous rectifier) must be minimized.
4. Grounding considerations:
   – The first priority in designing grounding connections is to confine the high peak currents that charge and discharge the MOSFET gates to a minimal physical area. This will decrease the loop inductance and minimize noise issues on the gate terminals of the MOSFETs. The gate driver should be placed as close as possible to the MOSFETs.
   – The second consideration is the high current path that includes the bootstrap capacitor, the bootstrap diode, the local ground referenced bypass capacitor, and the low side MOSFET body diode. The bootstrap capacitor is recharged on a cycle-by-cycle basis through the bootstrap diode from the ground referenced VDD bypass capacitor. The recharging occurs in a short time interval and involves high peak current. Minimizing this loop length and area on the circuit board is important to ensure reliable operation.
5. The resistor on the RDT pin must be placed very close to the IC and separated from the high current paths to avoid noise coupling to the time delay generator which could disrupt timer operation.

POWER DISSIPATION CONSIDERATIONS

The total IC power dissipation is the sum of the gate driver losses and the bootstrap diode losses. The gate driver losses are related to the switching frequency (f), output load capacitance on LO and HO (C_L), and supply voltage (V_{DD}) and can be roughly calculated as:

$$P_{DGATES} = 2 \bullet f \bullet C_L \bullet V_{DD}^2 \quad (1)$$

There are some additional losses in the gate drivers due to the internal CMOS stages used to buffer the LO and HO outputs. The following plot shows the measured gate driver power dissipation versus frequency and load capacitance. At higher frequencies and load capacitance values, the power dissipation is dominated by the power losses driving the output loads and agrees well with the above equation. This plot can be used to approximate the power losses due to the gate drivers.

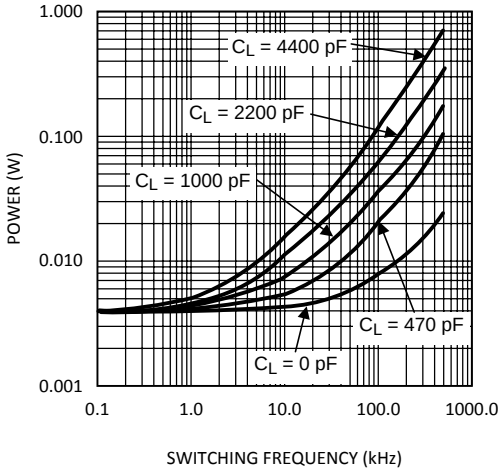


Figure 20. Gate Driver Power Dissipation (LO + HO)
V_{CC} = 12V

HS TRANSIENT VOLTAGES BELOW GROUND

The HS node will always be clamped by the body diode of the lower external FET. In some situations, board resistances and inductances can cause the HS node to transiently swing several volts below ground. The HS node can swing below ground provided:

1. HS must always be at a lower potential than HO. Pulling HO more than -0.3V below HS can activate parasitic transistors resulting in excessive current flow from the HB supply, possibly resulting in damage to the IC. The same relationship is true with LO and VSS. If necessary, a Schottky diode can be placed externally between HO and HS or LO and GND to protect the IC from this type of transient. The diode must be placed as close to the IC pins as possible in order to be effective.
2. HB to HS operating voltage should be 15V or less. Hence, if the HS pin transient voltage is -5V, VDD should be ideally limited to 10V to keep HB to HS below 15V.
3. Low ESR bypass capacitors from HB to HS and from VCC to VSS are essential for proper operation. The capacitor should be located at the leads of the IC to minimize series inductance. The peak currents from LO and HO can be quite large. Any inductances in series with the bypass capacitor will cause voltage ringing at the leads of the IC which must be avoided for reliable operation.

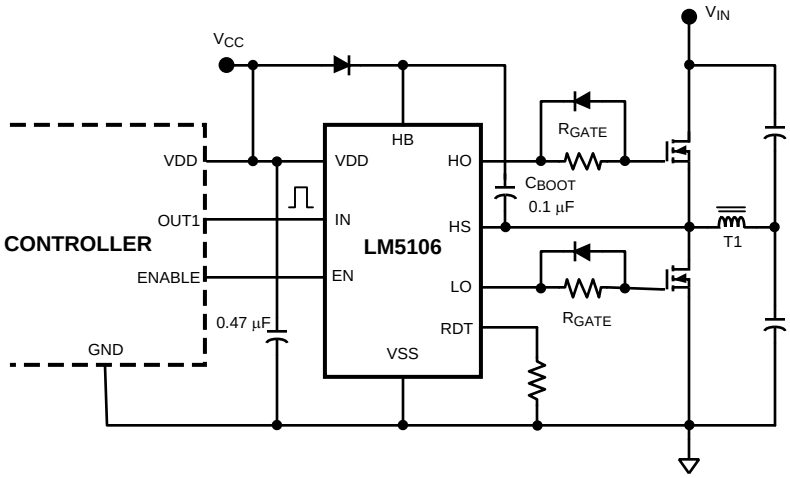


Figure 21. LM5106 Driving MOSFETs Connected in Half-Bridge Configuration

REVISION HISTORY

Changes from Revision B (March 2013) to Revision C	Page
• Changed layout of National Data Sheet to TI format	10

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
LM5106MM	NRND	VSSOP	DGS	10	1000	TBD	Call TI	Call TI	-40 to 125	5106	
LM5106MM/NOPB	ACTIVE	VSSOP	DGS	10	1000	Green (RoHS & no Sb/Br)	CU SN	Level-1-260C-UNLIM	-40 to 125	5106	Samples
LM5106MMX/NOPB	ACTIVE	VSSOP	DGS	10	3500	Green (RoHS & no Sb/Br)	CU SN	Level-1-260C-UNLIM	-40 to 125	5106	Samples
LM5106SD/NOPB	ACTIVE	WSON	DPR	10	1000	Green (RoHS & no Sb/Br)	CU NIPDAU | CU SN	Level-1-260C-UNLIM	-40 to 125	L5106SD	Samples
LM5106SDX/NOPB	ACTIVE	WSON	DPR	10	4500	Green (RoHS & no Sb/Br)	CU NIPDAU | CU SN	Level-1-260C-UNLIM	-40 to 125	L5106SD	Samples

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.
TBD: The Pb-Free/Green conversion plan has not been defined.
Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.
Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.
Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

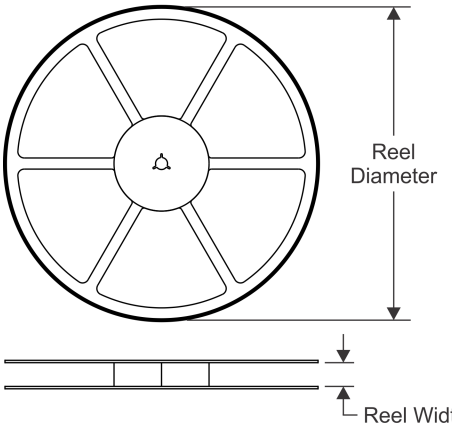
(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

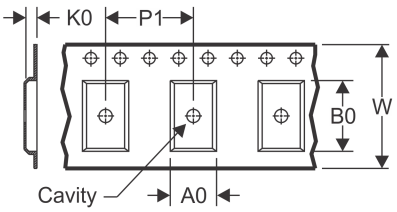
(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

TAPE AND REEL INFORMATION

REEL DIMENSIONS

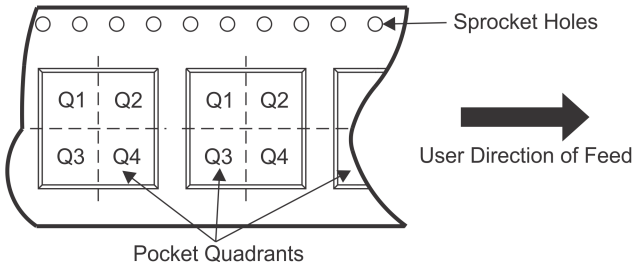


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

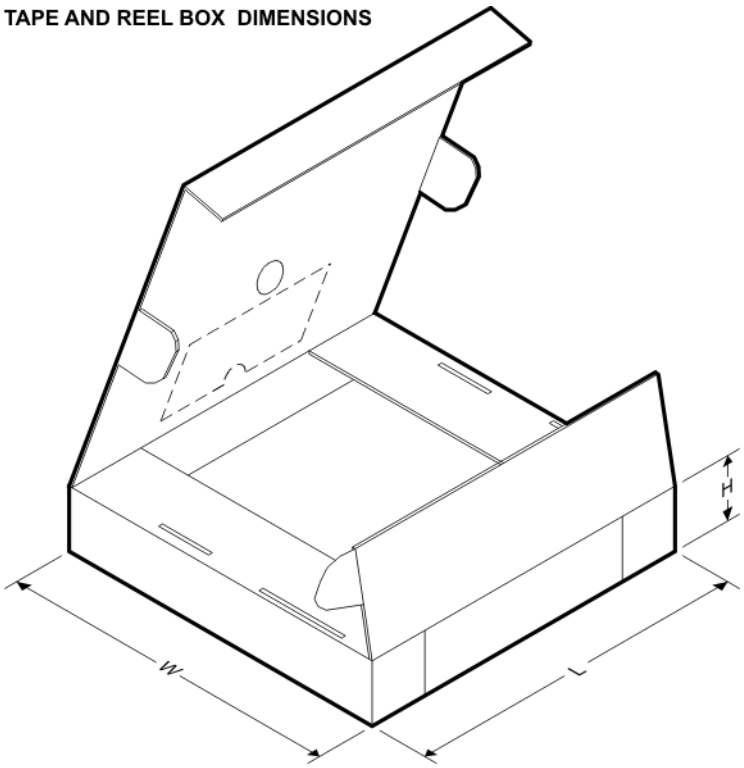
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
LM5106MM	VSSOP	DGS	10	1000	178.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
LM5106MM/NOPB	VSSOP	DGS	10	1000	178.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
LM5106MMX/NOPB	VSSOP	DGS	10	3500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
LM5106SD/NOPB	WSON	DPR	10	1000	180.0	12.4	4.3	4.3	1.1	8.0	12.0	Q1
LM5106SD/NOPB	WSON	DPR	10	1000	178.0	12.4	4.3	4.3	1.3	8.0	12.0	Q1
LM5106SDX/NOPB	WSON	DPR	10	4500	330.0	12.4	4.3	4.3	1.1	8.0	12.0	Q1
LM5106SDX/NOPB	WSON	DPR	10	4500	330.0	12.4	4.3	4.3	1.3	8.0	12.0	Q1

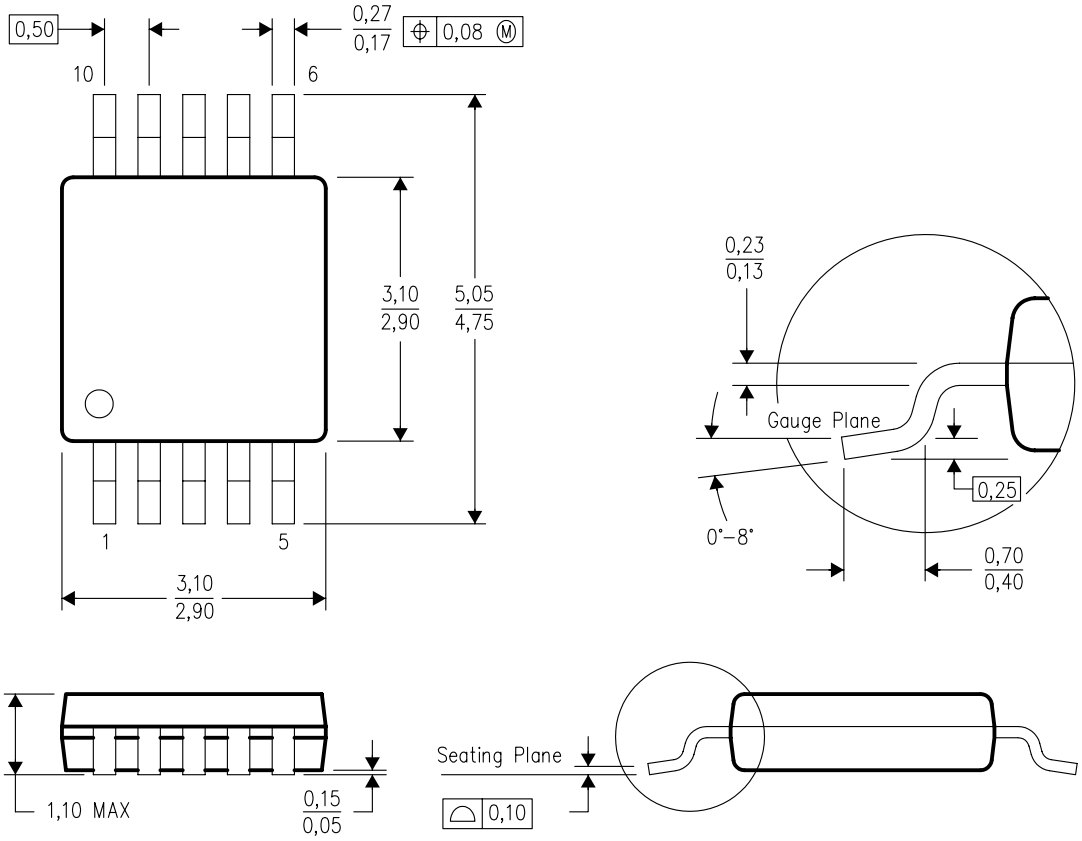
TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
LM5106MM	VSSOP	DGS	10	1000	210.0	185.0	35.0
LM5106MM/NOPB	VSSOP	DGS	10	1000	210.0	185.0	35.0
LM5106MMX/NOPB	VSSOP	DGS	10	3500	367.0	367.0	35.0
LM5106SD/NOPB	WSON	DPR	10	1000	203.0	203.0	35.0
LM5106SD/NOPB	WSON	DPR	10	1000	210.0	185.0	35.0
LM5106SDX/NOPB	WSON	DPR	10	4500	346.0	346.0	35.0
LM5106SDX/NOPB	WSON	DPR	10	4500	367.0	367.0	35.0

DGS (S–PDSO–G10) PLASTIC SMALL–OUTLINE PACKAGE



4073272/C 02/04

NOTES:
A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Body dimensions do not include mold flash or protrusion.
D. Falls within JEDEC MO–187 variation BA.

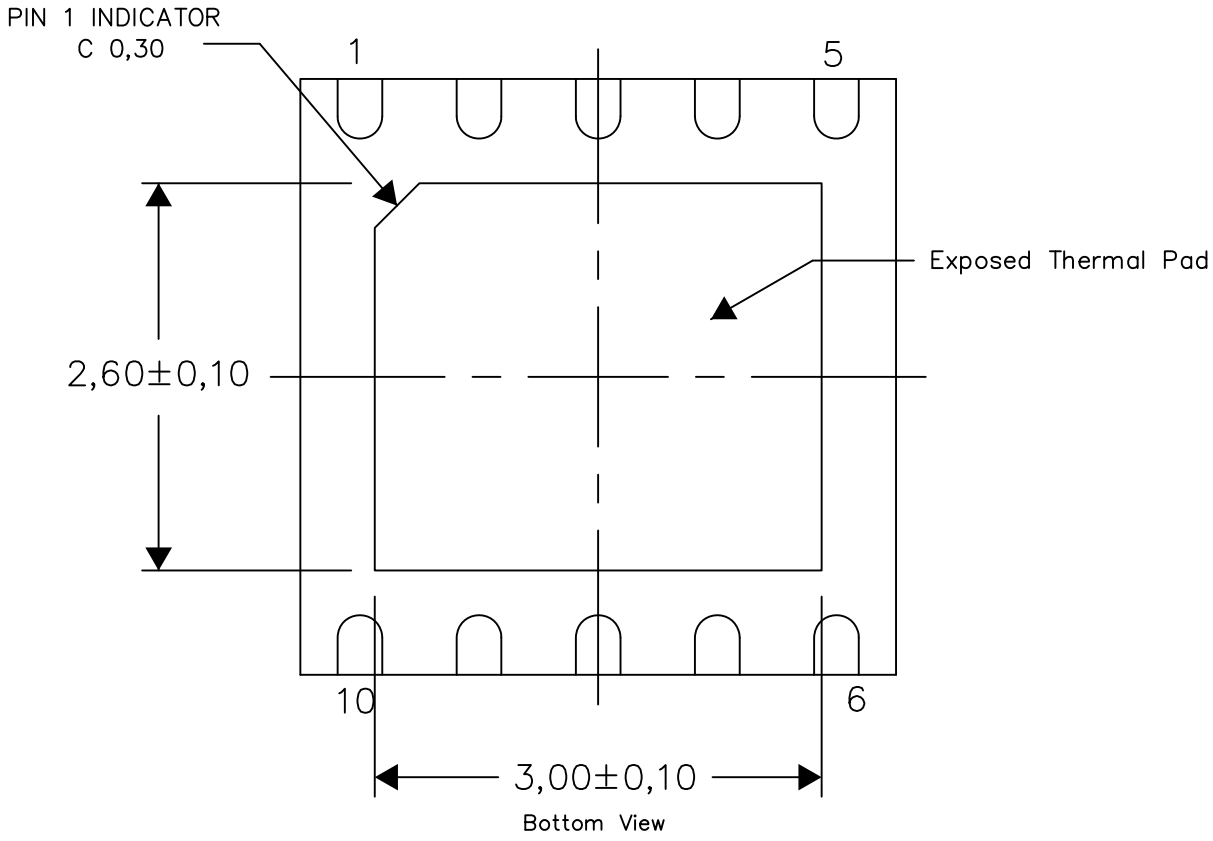
DPR (S–PWSON–N10) PLASTIC SMALL OUTLINE NO–LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No–Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.

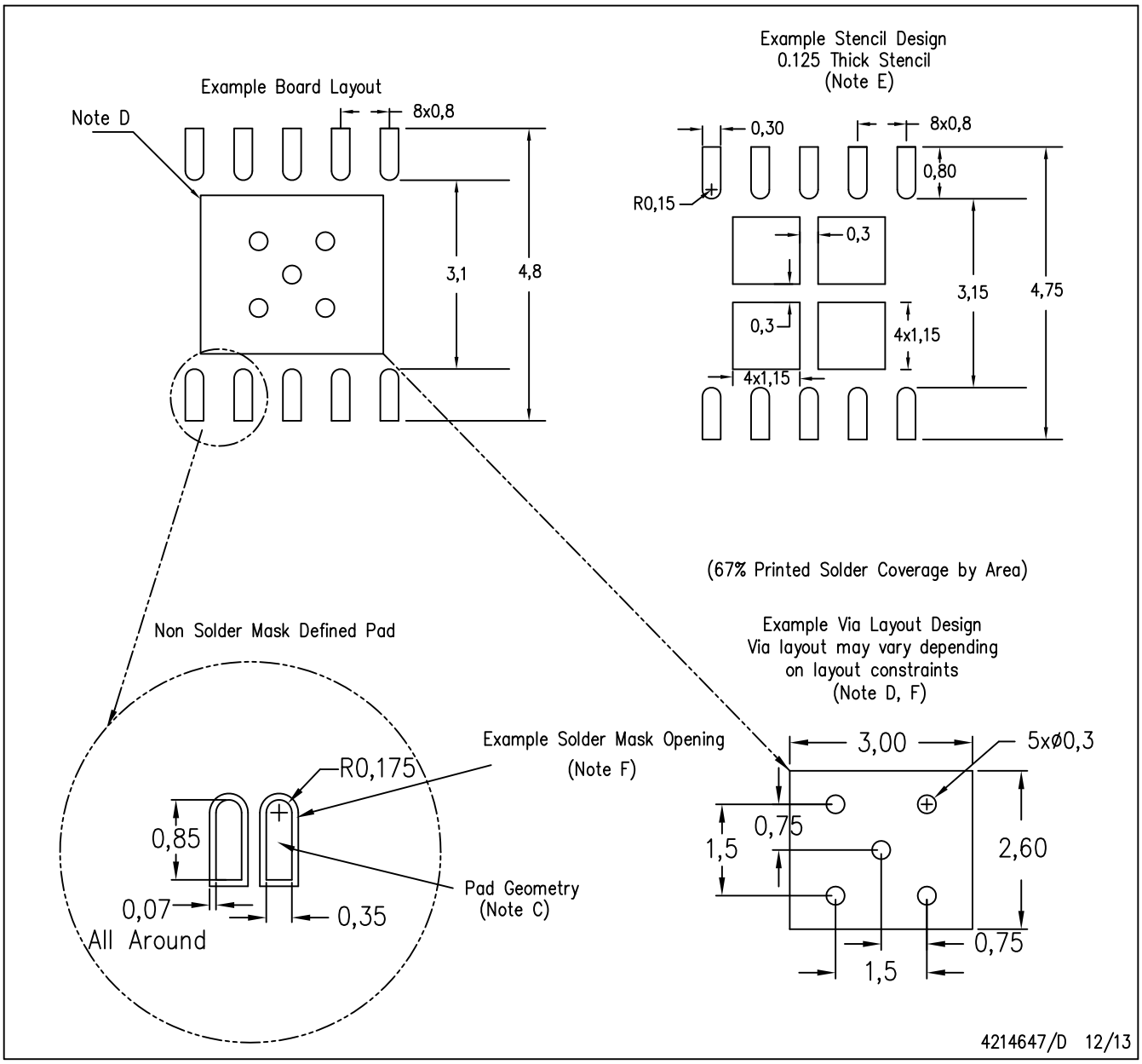


Exposed Thermal Pad Dimensions

4211551/C 12/13

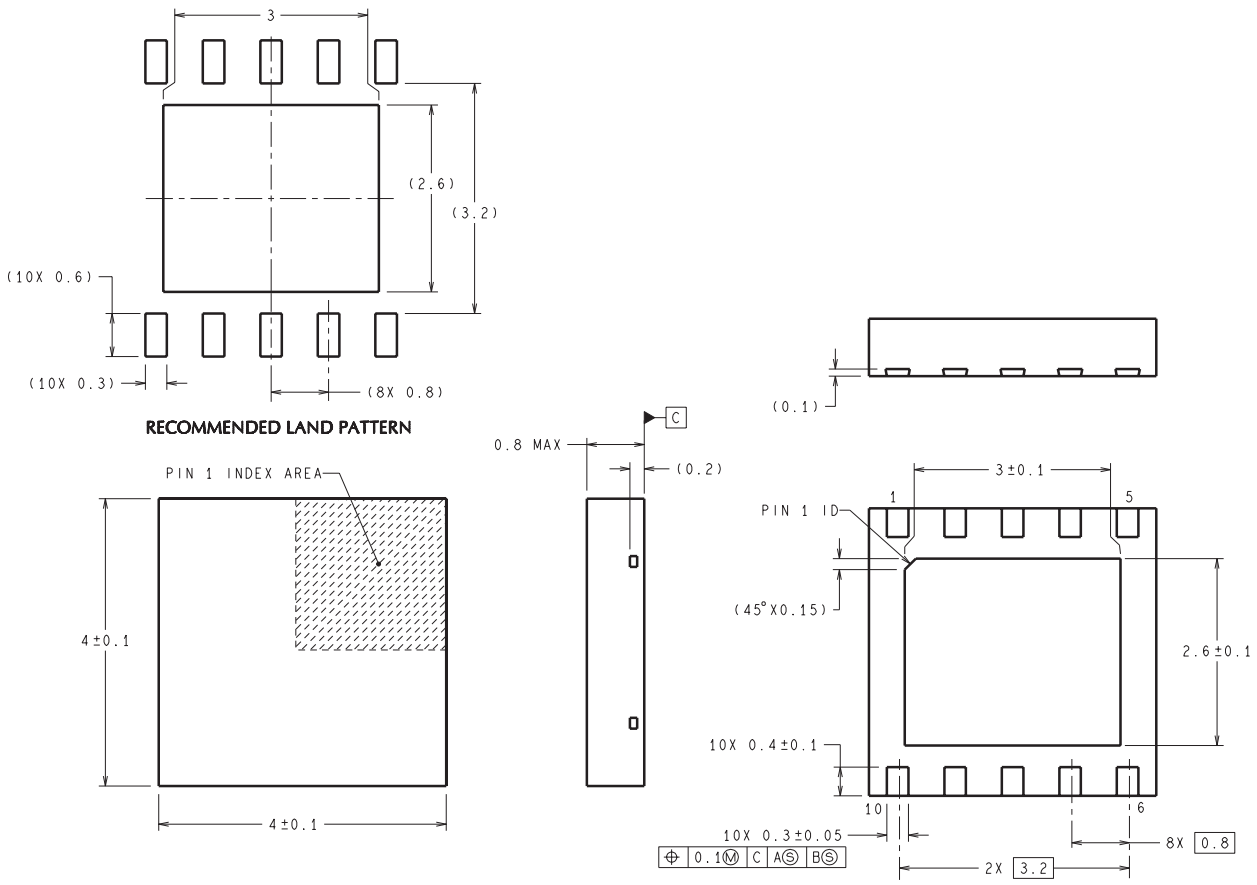
NOTES: All linear dimensions are in millimeters

DPR (S–PWSON–N10) PLASTIC SMALL OUTLINE NO–LEAD



NOTES:
A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Publication IPC–7351 is recommended for alternate designs.
D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat–Pack Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <http://www.ti.com>.
E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
F. Customers should contact their board fabrication site for recommended solder mask tolerances and via tenting recommendations for vias placed in the thermal pad.

DPR0010A



DIMENSIONS ARE IN MILLIMETERS

SDC10A (Rev A)

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